Abstract of the Disclosure

In a defect inspection tool, since assigning an inspection recipe required for inspection, is a significantly laborious and time-consuming operation, this operation load is one of the causes of reduction in tool availability and thus needs to be relieved.

The present invention provides a scheme of: assigning a plurality of sets of image acquisition conditions, executing inspection using each of the sets of conditions, classifying all detected defects into real defects and false defects by use of an automatic defect classification function, and thus automatically selecting, from the plurality of sets of conditions, a set of conditions ideal for detection.

Also, efficiency can be further improved by creating a defect OR file not causing any results of a plurality of inspections to overlap.